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## APPLICANTS

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Masami Mori, Tenri-shi, JAPAN;\*\* CONTINUING DATA \*\*\*\*\* *None/V,N*\*\* FOREIGN APPLICATIONS \*\*\*\*\* *Yes W,N*  
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Foreign Priority claimed 35 USC 119 (a-d) conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance	STATE OR COUNTRY JAPAN	SHEETS DRAWING 25	TOTAL CLAIMS 33	INDEPENDENT CLAIMS 2
Verified and Acknowledged  Examiner's Signature <i>V. Henry</i>	Initials				

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## TITLE

Semiconductor testing apparatus and semiconductor testing method

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